

<b>Notice of References Cited</b>		Application/Control No. 10/611,996	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner John P. Sheehan	Art Unit 1742	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,478,897	11-2002	Izumida et al.	148/428
B	US-6,475,427	11-2002	Deshmukh et al.	419/8
C	US-6,200,688	03-2001	Liang et al.	428/544
D	US-5,938,543	08-1999	McGeeney et al.	473/324
E	US-4,692,305	09-1987	Rangaswamy et al.	420/436
F	US-2003/0000341	01-2003	Amick, Darryl D.	75/352
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	59-70744	04-1984	Japan	Yabuki et al.	420/448
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
U	Derwent Abstract 2003-842132 for Patent Document No. TW537916A June 2003	
V		
W		
X		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.